

Search Notes

Application/Control No.

10/066,173

Examiner

Hanh Nguyen

Applicant(s)/Patent under
Reexamination

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Art Unit

2616

SEARCHED

Class	Subclass	Date	Examiner
370	204	11/14/2006	HN
	205		
	212		
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INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	11/14/2006	HN